Supplemental information

Low-cost architecture

for iron-based coated conductors

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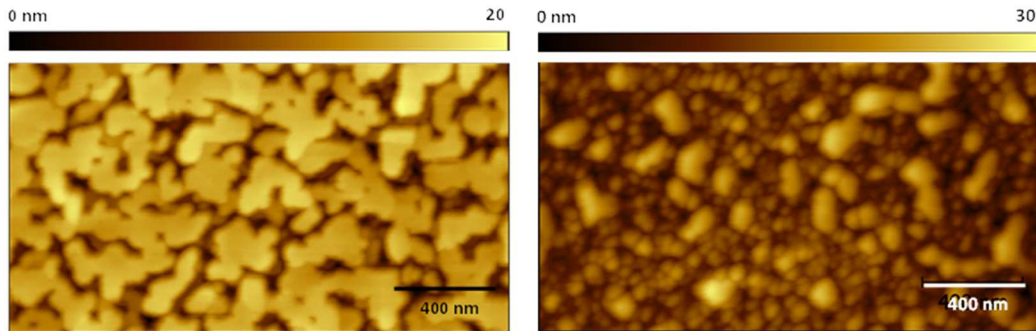
Supplementary Material

Fig. S1: AFM images of a CZO film obtained via MOD, related to Figure 1. Left:, morphology of the majority of the sample surface; Right: different morphology observed in some areas of the samples.
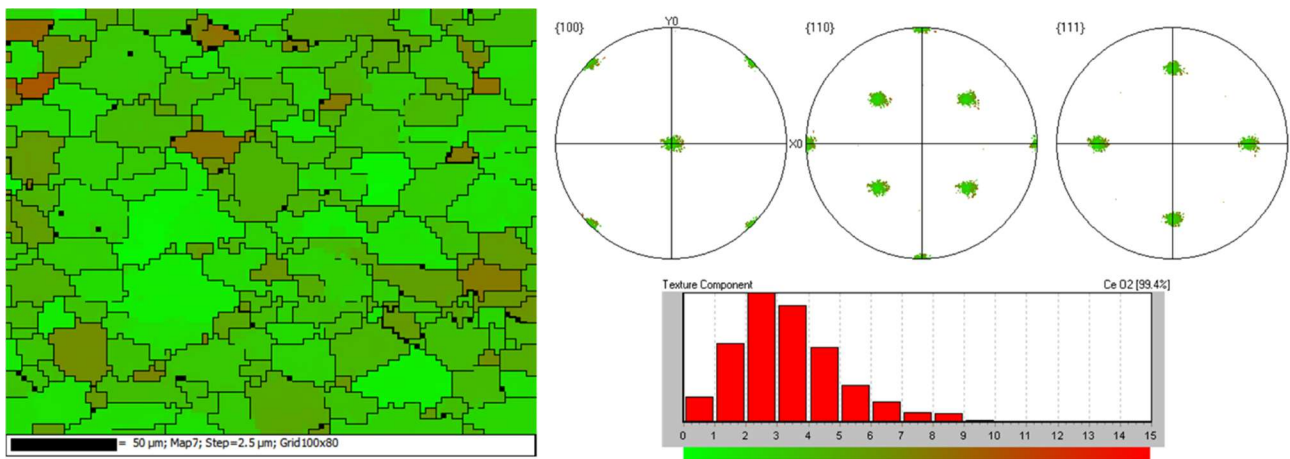

Fig. S2: EBSD analysis of a (MOD) CZO buffered Ni-W substrate, related to figure 1. Left: misorientation map with respect to the ideal orientation <110>/(001); Right: generated pole figures and misorientation distribution of the same area.
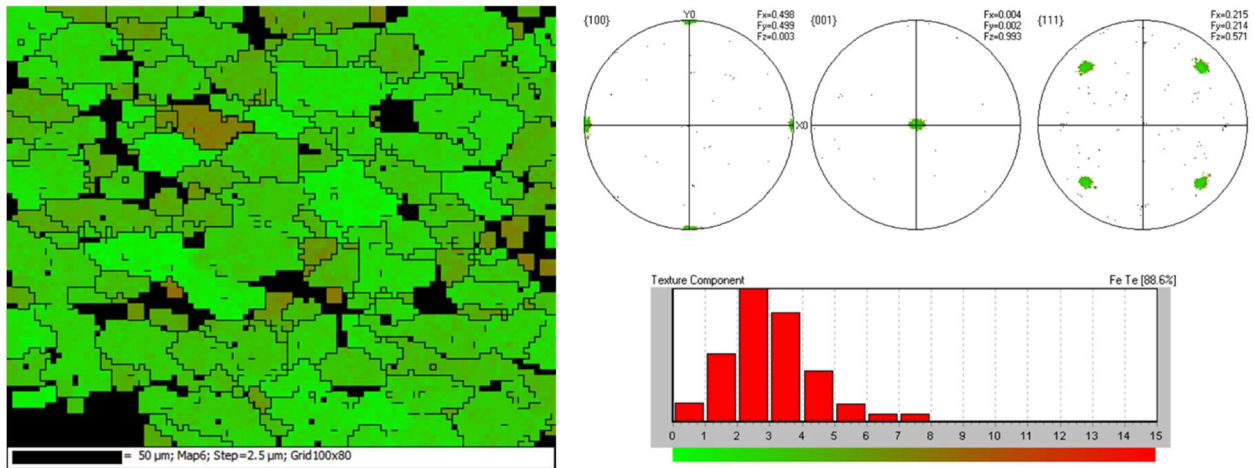
Fig. S3: EBSD analysis of a Fe(Se,Te) film grown on a (MOD) CZO buffered Ni-W substrate, related to Figure 4. Left: misorientation map with respect to the ideal orientation <100>/(001); Right, generated pole figures and misorientation distribution of the same area.
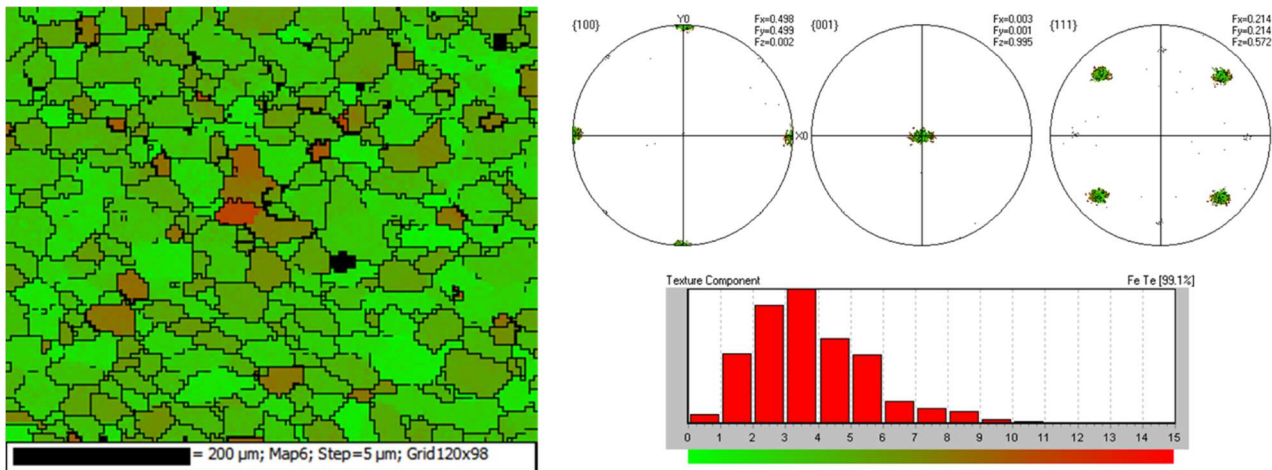

Fig. S4: EBSD analysis of a Fe(Se,Te) film grown on a (PLD) CeO$_2$ buffered Ni-W substrate, related to Figure 9: Left, misorientation map with respect to the ideal orientation <100>/(001); Right: generated pole figures and misorientation distribution of the same area.